



### GridPix: the ultimate electron detector for TPCs



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### **Future Lepton colliders:**

ILC ever? CLIC ever? CEPC Circular (China) Electron–Positron Collider

The first new experiment on any new large collider will be situated around a lepton colliding point

This experiment is likely to require a very large Time Projection Chamber (TPC):

- momentum resolution
- low scattering
- capable to handle track rate
- track separation
- track timing for trigger ID
- dE/dX measurement





### GridPlx TPC Readout:

- spark protection
- transverse spatial resolution
- spatial resolution in drift direction
- dE/dX
- track separation
- Ion back flow: Gated Grid
- Negative ion TPC

#### GridPix: integrated Micromegas grid onto TimePix chip.





MESA+ (TU Twente), IZM-Berlin, Bonn University

# Production of GridPixes: Spark protection

- a) Cleaning
- b) protection layer
- c) SU-8 covering
- d) Exposure with mask
- e) Aluminium layer is deposited
- f) Another layer of photoresist is applied, exposer with a mask creates a hole pattern, and the holes are chemically etched
- g) The wafer is diced
- h) The unexposed SU-8 is resolved



Thesis Stergios Tsigaridas, Next Generation GridPix

### **Spark protection**

- TimePix1 chips without protection: world record breaking chips: average lifetime 45 minutes
  TimePix1 chip with 4 μm Silicon-rich SiliconNitride: 90% well-protected chips
- 2013 After very aggressive cleaning procedure: 100% well-protected chips
- 2020 2021: Operating 8-Quad module (32 chips). No chip loss, after 1000 h of HV exposure





for single electrons:

- determined by diffusion, or
- for zero drift distance: pixel size (55  $\mu$ m)

This can't be better! All info from all primary electrons is extracted and processed

## Hit resolution in the drift direction



Single hit resolution in drift direction ! = ! + + (% - %)

Depends on

- !<sub>')</sub> from fit
- Diffusion \$\* from fit

Because of a large time walk error in hits with a low signal strength, an additional ToT cut ( > 0.50 μs) was imposed

## Time walk correction with the Timepix3



Time walk error: time of arrival depends on signal amplitude

Time walk can be corrected using Time over Threshold (ToT) as a measure for signal strength First order correction fitted and applied:

!" | mewalk = 
$$\frac{\$_!}{\%_{\#"}} + \%_{\$}$$

Distribution of residuals becomese more Gaussian after the time walk correction

#### This can't be better! All info from all primary electrons is extracted and processed

# dE/dX measurement



### **Count electrons along track:**

- count  $\delta$ -ray for 1 electron
- apply statistical correction from
- distance between electrons



### Track separation



Y LOTPO-Pixel Techeem Run 8009 Event 26 Biedd 1.0 T beam monentum 6 Gel

double track: contributes to track1 data until deviation is larger than to contribute to track2

#### Infinite track separation power

# Reducing the Ion back flow in a Pixel TPC

The Ion back flow can be reduced by adding a second grid to the device.

It is important that the holes of the grids are aligned. The Ion back flow is a function of the geometry and electric fields. Detailed simulations – validated by data - have been presented in LCTPC WP #326.

With a hole size of 25  $\mu$ m an IBF of 3 10<sup>-4</sup> can be achieved and the value for IBF\*Gain would be 0.6. Well below the specifications.



We plan to test this idea at Nikhef

Ion backflow	Hole 30 µm	Hole 25 µm	Hole 20 µm
Top grid	2.2%	1.2%	0.7%
GridPix	5.5%	2.8%	1.7%
Total	12 10-4	3 10-4	1 10-4
transparancy	100%	99.4%	91.7%

# Reducing the Ion back flow in a (Pixel) TPC

The Ion back flow can be reduced – while running at the Z:

- By installing a gating device and closing the gate after a trigger.
  - E.g.the Gating GEM as developed in the contect of the ILD experiment



LCWS19 presentation ILD gating GEM by Yumi Aoki (KEK)

Can we apply gating in Z collisions? High luminosity CEPC L =  $32-50 \ 10^{34} \ \text{cm}^{-2} \text{s}^{-1}$ . Time between Z interactions  $120-60 \ \mu \text{s}$  TPC drift takes  $30 \ \mu \text{s}$ . So events are separated in the TPC; gating is possible. Gate length of 20-60  $\mu$ s would stop the ions in triggered mode.

Problem is that the gating will lead to dead time and a data taking efficiency at high luminosities of  $\sim$ 85%-65% (for a 20 µs gate length).

## **Negative ion drift TPC**

- 1. primary electron forms  $CS_2^{-1}$  ion
- 2. ion drifts towards InGrid

93.6/5.0/1.4 gas mixture (by volume) of Ar/iC<sub>4</sub>H<sub>10</sub>/CS<sub>2</sub>

3. electron is freed in strong avalanche field



Figure 5: Drift time distribution for 400 laser pulses per z-position, annotated with the drift distance as recorded by the laser stage.



Figure 7: Drift time as a function of the drift distance for the majority and minority carriers. The statistical error is not shown, because it is negligible compared to the systematic uncertainties.









8-Quad module, containing 32 GridPix chips



### Testbeams: DESY and Else in Bonn. At Nikhef there is a N<sub>2</sub> UV laser set up.

## Event displays 1 T



x in pixels

ESYLLCTPO-Pixel Testseam Aun 6000 Event 2 Biteld (10 Toean monentum 6 Gello

arrival time (ns)

## Event displays 0.5 T



## Event displays 1 T



x in pixels

DESYLCTPC-Pixel Testbeam Run 8889 Elect 42 Biled 1.0. Theam momentum 6 Gello

arrival time (ns)

## Event displays 0.5 T



## Event displays 1 T



arrival time (ns)

## Event displays 1 T



x in pixels

DESY LCTPC-Pixel Techean Ann 6000 Event 26 Bired 1.0 Theann nonnentum 6 Gel/o

arrival time (ns)

- Nikhef has pulled out of ILC collaboration Nikhef stopped with gaseous detectors
- All GridPix activity will be transported to University of Bonn (Klaus Desch et al.)
- **Future developments:**
- GridPix/InGrid manufacturing at new MEMS facility of Univ Bonn
- TPX-4 based GridPix
- A large TPC for Brookhaven Electron-Ion-Collider EIC